

Search Notes



Application/Control No.

09/817,225

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

AZUMA, NOBUHIRO

Art Unit

3629

SEARCHED

| Class | Subclass | Date | Examiner |
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| 705 | 1 | 3/06 | DN |
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)

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| I US | 3/06 | DN |
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| II FOREIGN | | |
| 1. EPO | | |
| 2. JPO | | |
| 3. Derwent | | |
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